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Description

LC5202D is non-isolated type driver IC for LED lighting which can achieve high efficiency in simple circuitry. Its compact package which includes output MOSFET and controller, and low external components are suitable for small lighting equipment which requires saving space, like LED light bulb.

Its high voltage capability allows direct connection to rectified AC supply.

Protection features ensure safety LED drive.

Applications

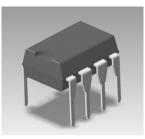
- LED Lighting equipment
- LED Light bulb

♦Features

- DIP8Package Output MOSFET and controller are included in one package.
- High voltage supply input Able to direct connection to rectified AC supply.
- Built-in constant current controller
 - PWM mode current control circuitry.
 - Adjustable output current by input voltage to Ref pin.

♦Package

Package: DIP8

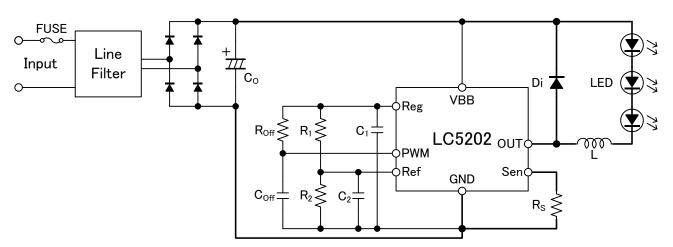


Main Specification

MOSFET Output Current Main Supply Voltage 250V (MIN), 2.2Ω (MAX) 0.5A (MAX) 250V (MAX)

- External PWM
 PWM signal input to PWM pin enables dimming.
 Low signal shuts off output current.
- Under voltage lockout protection (UVLO)
 Prevents malfunction when supply voltage is low.
- Over current protection (OCP) Latched in response to the load short condition.
- Thermal Shutdown protection (TSD)
 Protects IC from damage due to excess temperature, auto-restart when temperature drops below threshold

Typical application circuit





1 Scope

The present specifications shall apply to a LED driver IC for LED lighting, LC5202D.

2 Outline

| Туре | Hybrid Integrated Circuit | | |
|--------------|--------------------------------|--|--|
| Structure | Plastic Molded (Transfer Mold) | | |
| Applications | LED Lighting | | |

3 Absolute Maximum Ratings (Ta=25°C)

| Parameter | Terminal | Symbol | Ratings | Units | Remarks |
|---------------------------------|----------|------------------|----------------------------------|-------|-------------------------------|
| Main Power Supply Voltage | 6-8 | V_{BB} | 250 | V | |
| Output MOSFET Breakdown Voltage | 5-4 | Vo | 250 | V | |
| Output Current | 5-4 | Io | 0.5^{*1} | А | Exclude t _w <1µs |
| Ref Input Voltage | 3-8 | V_{Ref} | $-0.3 \sim V_{\text{Reg}} + 0.3$ | V | |
| Sense Voltage | 4-8 | V_{Sen} | -0.3~4 | V | Exclude t _w <1µs |
| Allowable Power Dissipation | — | P _D | 1.73 ^{**2} | W | Mounted on PWB ^{**3} |
| Junction Temperature | — | T_j | 150 | °C | |
| Operating Temperature Range | | Ta | -40~105 | °C | |
| Storage Temperature Range | | T _{stg} | -40~150 | °C | |

1 Output current rating may be limited by duty cycle, ambient temperature, and heat sinking. Under any set of conditions, do not exceed the specified junction temperature (T_j).

*2 Allowable Power Dissipation depends on PWB pattern layout.

X3 Mounted on Sanken evaluation board.

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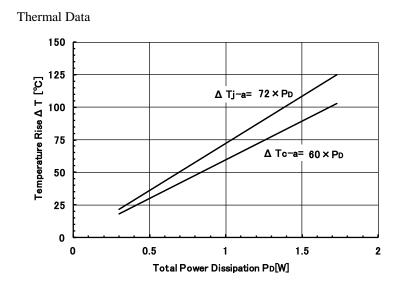
| Doromotor | Terminal | Symbol | Ratings | | | Units | D |
|---|----------|----------------------|----------------------|------------------|---------------|-------|-------------------------|
| Parameter | | | MIN | ТҮР | MAX | Units | Remarks |
| Main Power Supply Current | 6-8 | I_{BB} | | 2 | | mA | At enable |
| Main Fower Suppry Current | 6-8 | I _{BBs} | | 0.8 | 1.2 | mA | At disable |
| Drain-Source Breakdown Voltage | 5-4 | V _{DS(BR)} | 250 | | _ | V | I _D =1mA |
| Output MOS-FET On Resistance | 5-4 | R _{DS(on)} | | 1.2 | 2.2 | Ω | I _D =0.5A |
| Body Diode Forward Voltage | 4-5 | V_{F} | | 0.7 | 1.0 | V | I _F =0.5A |
| Reg Output Voltage | 1-8 | V_{Reg} | 11.5 | 12 | 12.5 | V | I _{Reg} =0.1mA |
| Reg Maximum Output Current | 1-8 | I _{Reg} | | _ | 2 | mA | |
| Maximum PWM Frequency | 2-8 | f_{clk} | 200^{*4} | | | kHz | duty=50% |
| Ref Input Voltage Range | 3-8 | V_{Ref} | 0 | | 1 | V | |
| Ref Input Current | 3-8 | I _{Ref} | | ± 10 | | μΑ | |
| Sense Input Voltage | 4-8 | V _{Sen} | V _{Ref} -30 | V _{Ref} | V_{Ref} +30 | mV | |
| Sense Input Current | 4-8 | I _{Sen} | | ±10 | | μΑ | |
| Over Current Protect Voltage | 4-8 | V _{OCP} | | 3 | | V | |
| Under Voltage Lock Out Threshold (Turn On) | 6-8 | V _{UVLOon} | | 14 | | V | |
| Under Voltage Lock Out Threshold (Turn Off) | 6-8 | V_{UVLOoff} | | 13 | | V | |
| Thermal Shutdown Threshold | — | T _{TSD} | — | 150 | _ | °C | Temperature |
| Thermal Shutdown Hysteresis | — | T _{TSDhys} | | | | | |
| Blanking Time | | t _{BLK} | | 400 | | ns | |
| Switching Time | 5-4 | t _r | | 20 | | ns | Io=0.4A |
| Switching Time | 5-4 | t _f | — | 50 | | ns | Io=0.4A |

4 Electrical Characteristic (Ta=25°C, V_{BB}=140V, Unless Otherwise Noted.)

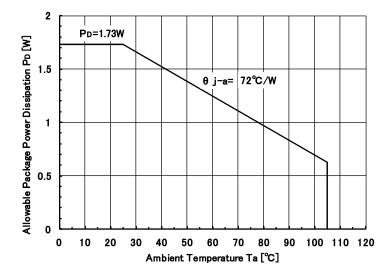
※4 Operation at a PWM frequency greater than 200kHz is possible but not warranted.

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Power Dissipation versus Ambient Temperature

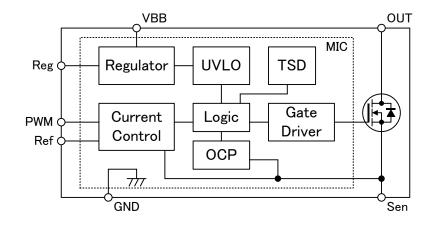


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5 Functional Block Diagram (Pin assignment)



Pin Assignment

| Number | Name | Function | | |
|--------|------|-------------------------------------|--|--|
| 1 | Reg | 12V Internal regulator output pin | | |
| 2 | PWM | Connect to PWM Off-Time Setting C&R | | |
| 3 | Ref | Reference Voltage for PWM Control | | |
| 4 | Sen | Output-current detection pin | | |
| 5 | OUT | Output pin | | |
| 6 | VBB | Supply voltage pin | | |
| 7 | _ | _ | | |
| 8 | GND | Device ground pin. | | |

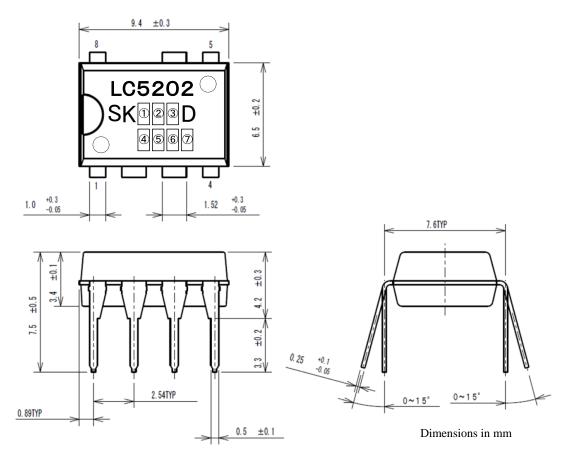


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6 Package

6.1 Package Drawing and Material

• DIP8 Package



| Terminal material: Cu | Marking | | | | | |
|--------------------------|------------|----------------------------|-------------------------|--|--|--|
| Terminal material: Cu | Position | Contents | Indication | | | |
| Terminal treatment: | 1 | The last digit of the year | 0 to 9 | | | |
| Solder plating (Pb-free) | 2 | The Month | 1 to 9,0,N,D | | | |
| | 3 | The week | 1 to 3 | | | |
| | 4 | | alphanumeric characters | | | |
| | 5 | Sanken Registration | | | | |
| | 6 | Number | | | | |
| | \bigcirc | | | | | |

6.2 Appearance

The body shall be clean and shall not bear any stain, rust or flaw.

6.3 Marking

The type number and lot number shall be clearly marked by laser so that cannot be erased easily.



7 Cautions and warnings

Since reliability can be affected adversely by improper storage environment and handling methods during Characteristic tests, please observe the following cautions.

7.1 Cautions for Storage

- Ensure that storage conditions comply with the standard temperature (5 to 35°C) and the standard relative humidity (around 40 to 75%) and avoid storage locations that experience extreme changes in temperature or humidity.
- Avoid locations where dust or harmful gases are present and avoid direct sunlight.
- Reinspect for rust in leads and solderability that have been stored for a long time.

7.2 Cautions for characteristic Tests and Handling

• When characteristic tests are carried out during inspection testing and other standard tests periods, protect the devices from surge of power from the testing device, shorts between the devices and the heatsink.

7.3 Considerations to protect the Products from Electrostatic Discharge

- When handling the devices, operator must be grounded. Grounded wrist straps be worn and should have at least $1M\Omega$ of resistance near operators to ground to prevent shock hazard.
- Workbenches where the devices are handled should be grounded and be provided with conductive table and floor mats.
- When using measuring equipment such as a curve tracer, the equipment should also be grounded.
- When soldering the devices, the head of a soldering iron or a solder bath must be grounded in other to prevent leak voltage generated by them from being applied to the devices.
- The devices should always be stored and transported in our shipping containers or conductive containers, or be wrapped up in aluminum foil.



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7.4 Others

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- In the case that you use our semiconductor devices or design your products by using our semiconductor devices, the reliability largely depends on the degree of derating to be made to the rated values. Derating may be interpreted as a case that an operation range is set by derating the load from each rated value or surge voltage or noise is considered for derating in order to assure or improve the reliability. In general, derating factors include electric stresses such as electric voltage, electric current, electric power etc., environmental stresses such as ambient temperature, humidity etc. and thermal stress caused due to self-heating of semiconductor devices. For these stresses, instantaneous values, maximum values and minimum values must be taken into consideration.

In addition, it should be noted that since power devices or IC's including power devices have large self-heating value, the degree of derating of junction temperature (Tj) affects the reliability significantly.

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